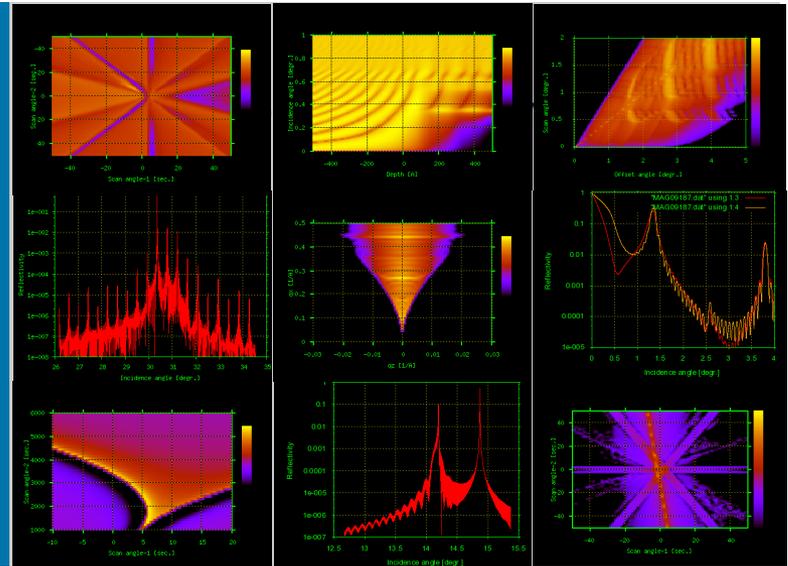


X-RAY SERVER: DYNAMICAL DIFFRACTION ON THE WEB. SCOPE, HISTORY, CAPABILITIES, AND PLANS



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Advanced Photon Source,
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October 2016, SOS Workshop, Trieste, Italy

What is X-ray Server?

X-Ray Server (x-server.gmca.aps.anl.gov) is a WWW-based computational server for modeling of X-ray diffraction, reflection and scattering. All software operates directly on the server and can be accessed remotely either from web browsers or from user software so that the server can be deployed as a software library or data fitting engine.

Goals:

- explore simplest ways to share scientific software with community using WWW.
- avoid porting software to multiple platforms and maintaining multiple versions.
- be able to collect feedback from users, correct errors and prevent misuse of programs beyond the limits of X-ray scattering models they implement.

Technology:

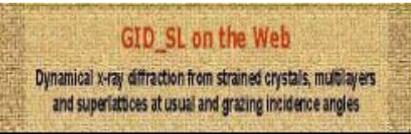
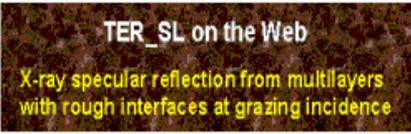
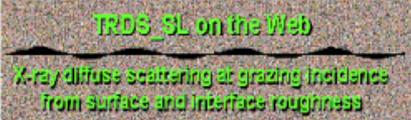
- http interface (CGI wrappers) to *unchanged* scientific software

History:

- online since 1997; free and no registration,
- served more than 2 million jobs,
- about 5000 IPs used it 10 or more times

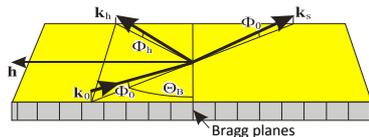
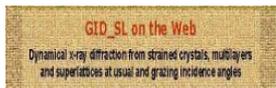
Software available through X-ray Server

<http://x-server.gmca.aps.anl.gov> (online since 1997)

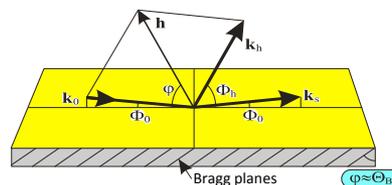
 	<p>Xoh interpolates dielectric susceptibilities for crystals and other materials in wide range of X-ray energies with the option to compare data from different DBs.</p> <p>Xoh+ provides search for Bragg planes in crystals under various conditions (Bragg angle, strong reflections...).</p>	1,262,567
 <p>Dynamical x-ray diffraction from strained crystals, multilayers and superlattices at usual and grazing incidence angles</p>	<p>GID_sl models X-ray diffraction curves from perfect and strained crystals, as well as multilayers for any Bragg-case diffraction with scans around arbitrary axes.</p>	724,776
 <p>X-ray specular reflection from multilayers with rough interfaces at grazing incidence</p>	<p>TER_sl calculates X-ray specular reflection and respective X-ray standing waves from multilayers with interface roughness.</p>	150,728
 <p>X-ray multiple Bragg/Laue diffraction</p>	<p>BRL models multiple Bragg diffraction of X-rays by perfect crystals including the cases of X-rays grazing along the surface and Bragg angles close to 90°.</p>	52,007
 <p>X-ray diffuse scattering at grazing incidence from surface and interface roughness</p>	<p>TRDS_sl calculates X-ray diffuse scattering for several models of interface roughness in multilayers.</p>	22,012
 <p>X-ray resonant specular reflection from magnetic multilayers</p>	<p>MAG_sl calculates X-ray resonant specular reflection from magnetic multilayers with interface roughness and transition layers.</p>	19,032

Based on 17 research papers; as of 2016/08/31 served **2,231,122 jobs**.

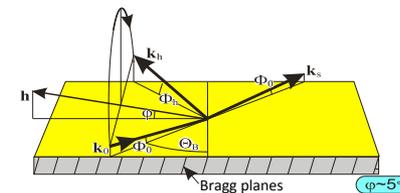
X-Server scope: GID_sl (diffraction)



Grazing incidence diffraction



Extremely asymmetric diffraction



Any non-coplanar diffraction

- Calculates Bragg diffraction from crystals with given profiles of normal lattice strains $da(z)/a$, dielectric susceptibilities $\chi_0(z)$, $\chi_h(z)$, and interface roughness height $\sigma(z)$. The profiles are specified layer-by-layer, which allows for flexibility
- Takes into account specular reflection and refraction of X-rays at crystal surface and interfaces in multilayers
- Works for any Bragg-case geometry and scans around any axis
- **Applications:** X-ray optics (monochromators) and semiconductor material science; examples: Stepanov, *et.al.* PRB **57**, 4829 (1998); Stepanov & Forrest, J.Appl.Cryst. **41**, 958 (2008); Stoupin *et.al.* PRB **86**, 054301 (2012)
- **Limitations:** No Laue cases, no bent crystals, no lateral strains, no instrumental convolutions

X-rays: Wavelength(A) / Energy(keV) = Line= ? Polarization=

Crystal: ? Sigma= A W0= Wh=

Bragg Reflection: Substrate da/a=

Geometry specified by: ?

-- Geometry parameter ([1,7]=incidence angle, [2,8]=exit angle, [6]=Bragg planes angle, [9]=g0/gh):

-- Surface plane ([1-5]): Miscut direction: Miscut angle:

Scan axis: ? Indices, if other scan axis: Invert scan axis

Scan limits: from to Scan points= Plot argument=

watch progress (single click, please!)

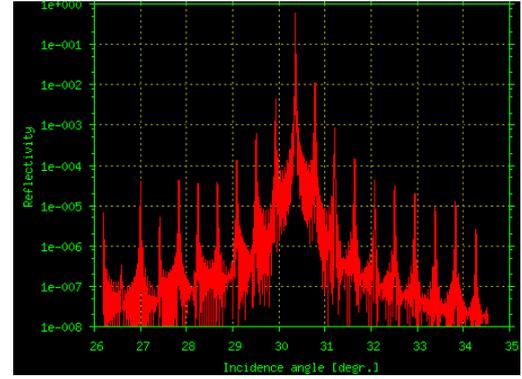
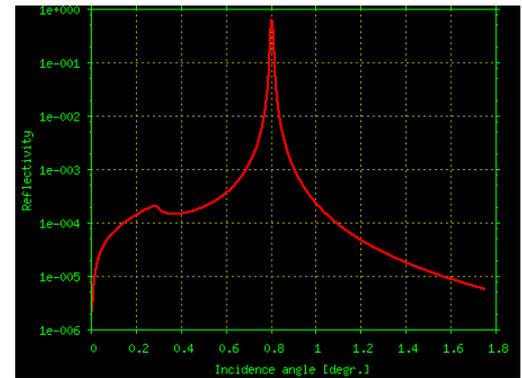
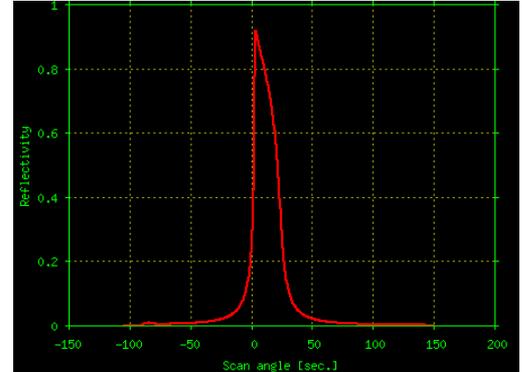
Top layer profile (optional):
 period=
 t= sigma= da/a= code= x= code2= x2= code3= x3= code4= x0= xh= xhdf= w0= wh=
 end period

```

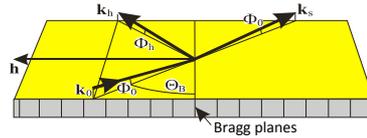
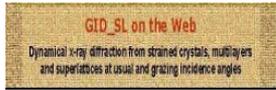
period=20
t=100 code=GaAs sigma=2
t=70 code=AlAs sigma=2 da/a=a
end period
    
```

Available codes:
 Crystals:
 AlAs
 AlP
 AlSb
 AlYO3
 BaTiO3
 Beril
 Beryllium
 Non-crystals:
 Al2O3
 B4C
 BeO
 BN
 Cr2O3
 CsI
 Fluorite
 Elements:

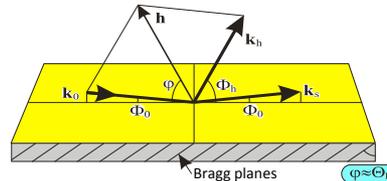
Web input form



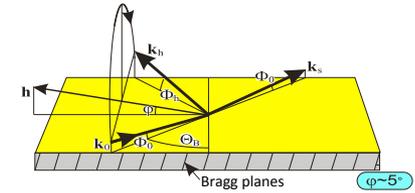
X-Server scope: TER_sl (specular reflection)



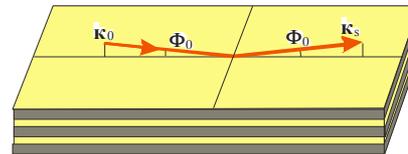
Grazing incidence diffraction



Extremely asymmetric diffraction



Any non-coplanar diffraction



- Calculates X-ray specular reflection from plain mirrors and multilayers with given profiles of electronic density (dielectric susceptibility) $\chi_0(z)$ and interface roughness height $\sigma(z)$ or transition layers.
- Converges faster than the Parratt recursive technique
- Also optionally calculates X-ray standing waves in multilayers
- **Applications:** X-ray optics (mirrors and multilayer mirrors and monochromators) and semiconductor material science
- **Limitations:** no curved mirrors, no instrumental convolutions

X-rays: Wavelength(A) / Energy(keV) = Line= ? Polarization=

Substrate: Database code: ?

Chemical formula: rho= g/cm³

Susceptibility x0 = () / format: x0=(Re(x0), Im(x0)); note: x0=2*delta /
 x0 correction: w0 = / this is used as: x0 = w0 * x0 /

Roughness: sigma = Angstrom **OR** Transition layer tr = Angstrom

Incidence angle limits: from to degr. Scan points=

Standing waves: Reference interface = (0=surface)
 Start offset = Angstrom
 End offset = Angstrom
 Number of offsets = (max = 401)

watch progress (single click, please!)

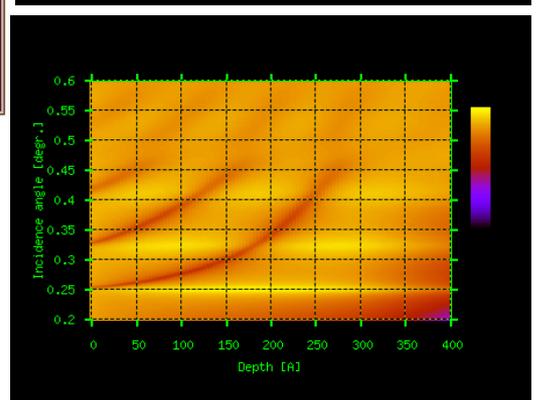
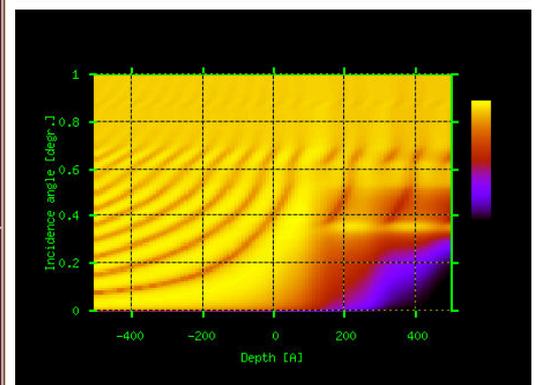
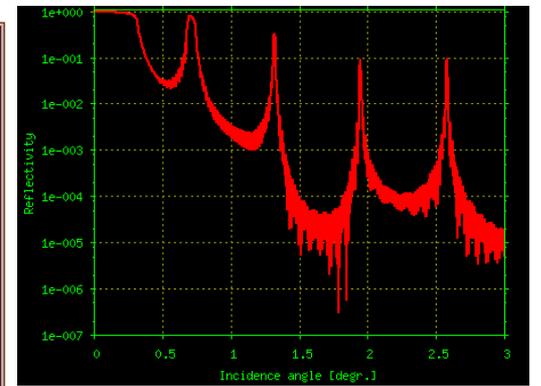
Top layer profile (optional):

t=20 w0=0.5 sigma=5 | surface oxide, organic contamination or dust
 period=20
 t=100 code=GaAs sigma=4
 t=70 code=AlAs sigma=4
 end period

(same "Submit" action as above; single click, please!)

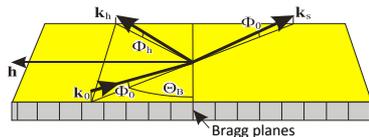
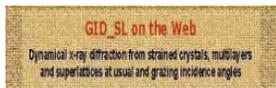
**Available codes:
 (use Copy/Paste)**

- Ac
- Ag
- Al
- Al2O3
- AlAs
- AlFe3
- AlN
- AlP

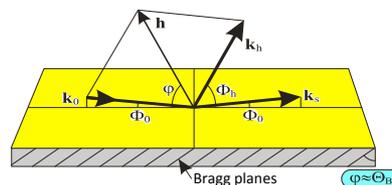


Web input form

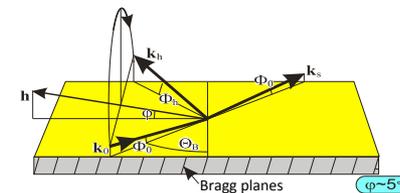
X-Server scope: BRL (multiple diffraction)



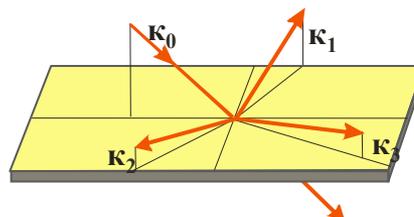
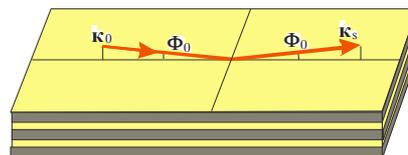
Grazing incidence diffraction



Extremely asymmetric diffraction



Any non-coplanar diffraction



- Calculates multiple Bragg diffraction from perfect plate-shaped crystals including the cases of X-rays grazing along the surface and Bragg angles close to 90° [Stepanov & Ulyanenkov, Acta Cryst. **A50**, 579 (1994)].
- Takes into account specular reflection and refraction of X-rays at crystal surface for grazing X-rays *only*.
- Helps to find multiple diffraction configurations and carry 2D Bragg scans around arbitrary axes
- **Applications:** X-ray optics (multiple diffraction effects including polarization glitches in X-ray monochromators); examples: Sutter, *et.al.* J.Appl.Cryst. **49**, 1209 (2016).
- **Limitations:** may lose precision for thick crystal plates, no instrumental convolutions, no lattice strains or curved crystals.

Target:

Crystal: ?

Surface: Base plane:

Miscut direction:

Miscut angle:

Reflections:

Reflex-1:

Reflex-2:

Index search range:

Min. Intensity filter:
($|x_h/x_0| * 100\% > \dots$)

X-rays:

Wavelength (Å):

Energy (keV):

Characteristic line: ?

Fixed by coplanar case

Fixed by Reflex-3:

Database Options for dispersion corrections df1, df2:

- Use X0h data (5-25 keV or 0.5-2.5 Å) -- *recommended*
- Use Henke data (0.01-30 keV or 0.4-1200 Å)
- Use Brennan-Cowan data (0.03-700 keV or 0.02-400 Å)

Crystal: **Silicon** Symmetry: **Cubic** X0h data: **Automatic DB choice**

Surface: base plane=(**1 1 1**) miscut direction=(**1 -1 0**) miscut angle=**0.** degr.

Thickness (microns):

X-rays: wavelength=**2.6344 Å** energy=**4.7063 keV** line=***none***

X-ray polarization: Angle to pi0 for mode [2]:

Scan limits (Theta1): from to points =

Scan limits (Theta2): from to points =

Scan axes: Scan angle units:

Specified reflections:

Reflex1 = (**1 1 1**) QB = 24.840 degr. $|x_h/x_0| = 52.895\%$ $|\alpha/x_0| = 0.105E-10$

Reflex2 = (**2 2 0**) QB = 43.314 degr. $|x_h/x_0| = 60.859\%$ $|\alpha/x_0| = 0.210E-10$

Reflex3 = (**3 1 1**) QB = 53.552 degr. $|x_h/x_0| = 39.863\%$ $|\alpha/x_0| = 0.700E-11$

Additional reflections search results (you can select up to 8 planes if available):
Searching from (**-5 -5 -5**) to (**5 5 5**) Intensity filter $|x_h/x_0| > 0.100\%$

Reflex4 = (**1 -1 1**) QB = 24.840 degr. $|x_h/x_0| = 52.895\%$ $|\alpha/x_0| = 0.105E-10$

Reflex5 = (**2 -2 0**) QB = 43.314 degr. $|x_h/x_0| = 60.859\%$ $|\alpha/x_0| = 0.210E-10$

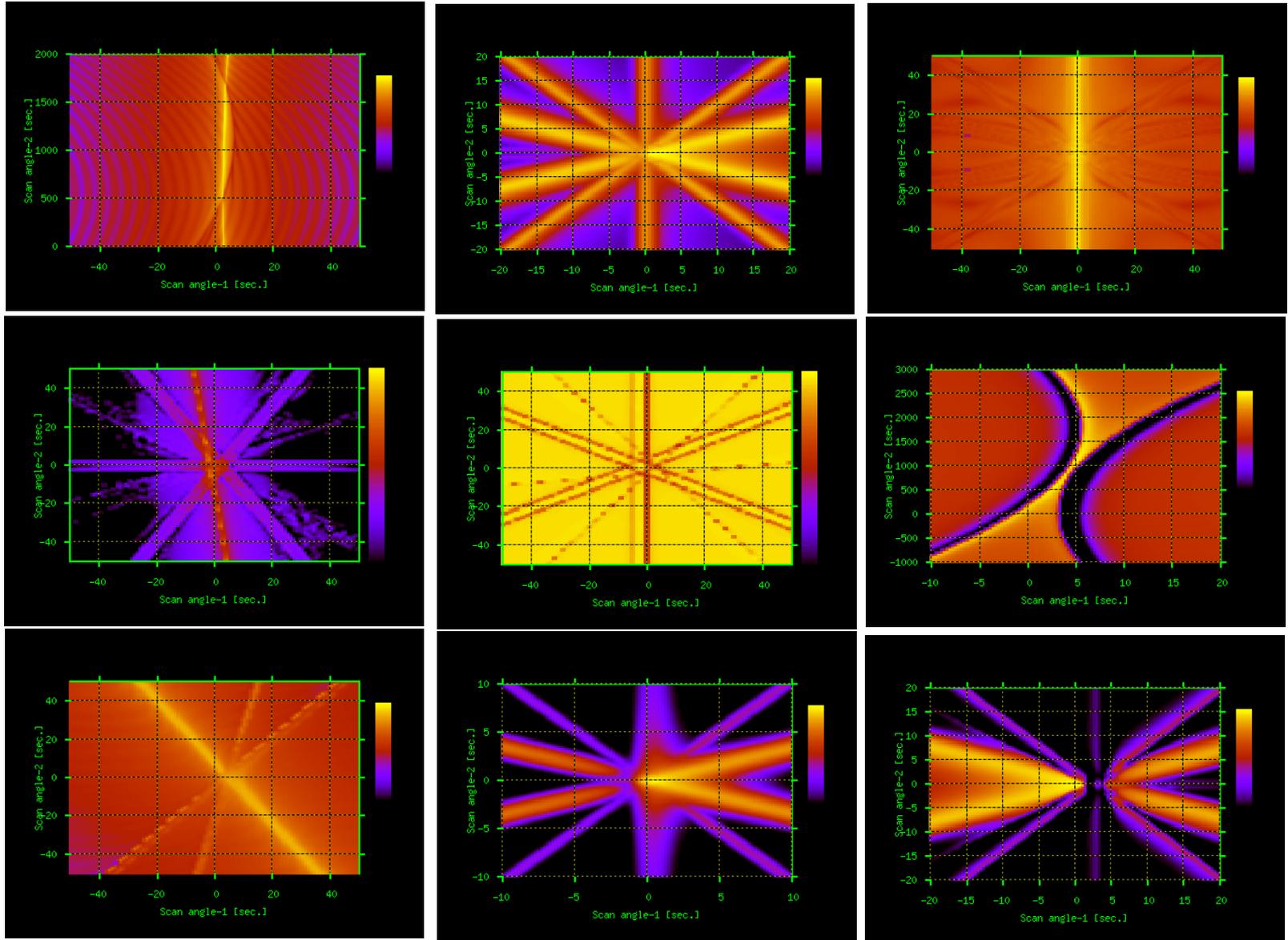
Reflex6 = (**3 -1 1**) QB = 53.552 degr. $|x_h/x_0| = 39.863\%$ $|\alpha/x_0| = 0.350E-10$

Reflex7 = (**4 0 0**) QB = 75.964 degr. $|x_h/x_0| = 50.816\%$ $|\alpha/x_0| = 0.280E-10$

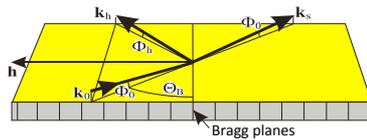
← Step-1

↪ Step-2

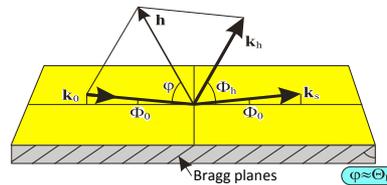
Web input forms



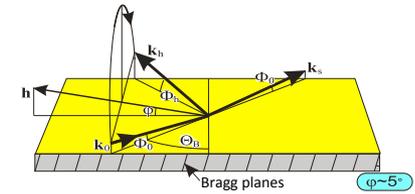
X-Server scope: TRDS_sl (roughness scattering)



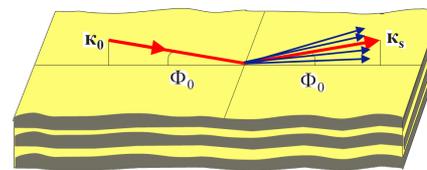
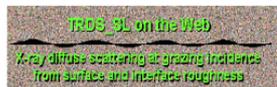
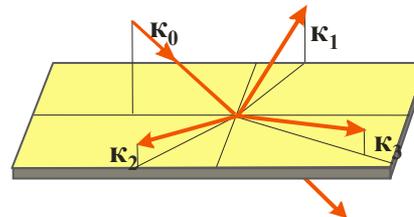
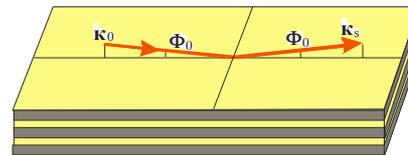
Grazing incidence diffraction



Extremely asymmetric diffraction



Any non-coplanar diffraction



- Calculates X-ray diffuse scattering from interface roughness in multilayers [Kaganer, Stepanov & Koehler, PRB. **52**, 16369 (1995)].
- Implements modeling for 10 different types of roughness correlations between the layers.
- **Applications:** X-ray optics (X-ray mirrors and multilayer mirrors quality evaluation) and semiconductor material science.

X-rays: Wavelength(A) / Energy(keV) = 1.540562 Line= Cu-Ka1 ? Polarization= Sigma

Substrate: Database code: GaAs ? X0h data (5-25keV; 0.5-2.5A)

Chemical formula: rho= g/cm³

Susceptibility x0 = () / format: x0=(Re(x0), Im(x0)); note: x0=2*delta/
x0 correction: w0 = / this is used as: x0 = w0 * x0 /

Roughness: sigma = Angstrom / this is rms roughness height /

Type of scan: Q-scans at fixed 2Q Units for Q,2Q: degr. Units for qx,qz: 1/A

Scan limits: from to points=

Offset limits: from to points=

Compute at specular rod: scattering reflection

Accelerators: Use K instead of exp(K)-1 Use semi-Born approximation

Roughness: lateral correlation length= A vertical correlation length= A jaggedness=
angle of skew transfer= degr.

Models:

- Uncorrelated roughness
- Completely correlated roughness
- Ming's model
- Lagally's model lateral size of vertically correlated roughness= A
- Holy's model
- Spiller's model (*very slow!*)

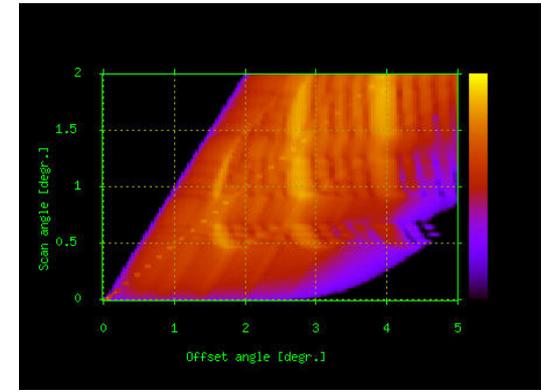
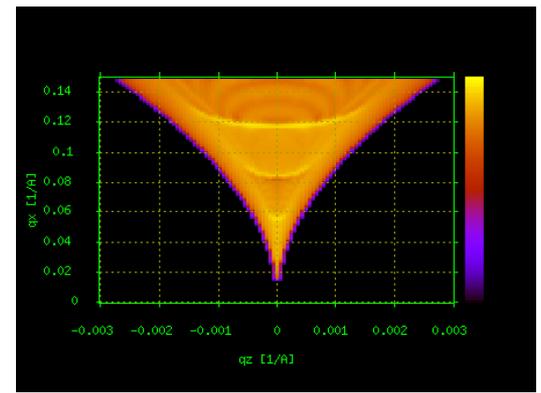
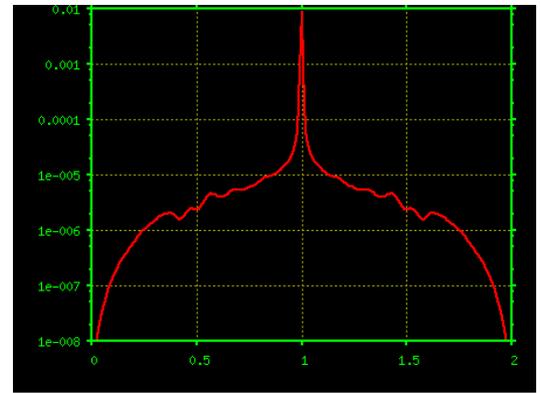
Data for all Pukite's models:

- miscut angle= degr. Add affine roughness
- Classic Pukite's model
- Smoothed Pukite's model effective rms height of steps= A
- Pershan's model terraces size spread= A

watch progress (single click, please!)

Top layer profile (optional):
period=
t= sigma= tr= code= rho= x= code2= x2= code3= x3= code4= x0= w0=
end period

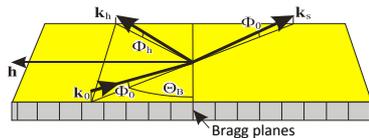
Available codes:
(use Copy/Paste)
Ac
Ag
Al
Al2O3
...



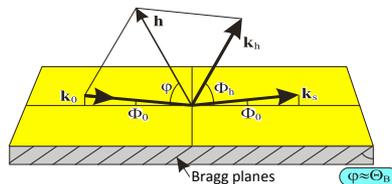
Web input form

X-Server: MAG_sl (resonance magnetic scattering)

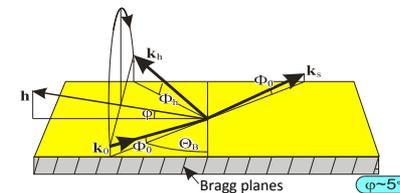
GID SL on the Web
 Dynamical x-ray diffraction from strained crystals, multilayers and superlattices at usual and grazing incidence angles



Grazing incidence diffraction

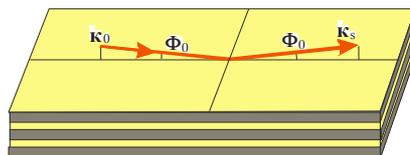


Extremely asymmetric diffraction

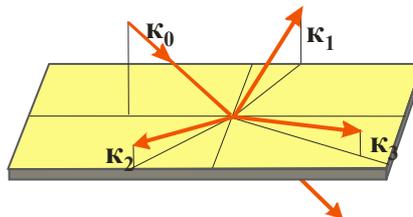


Any non-coplanar diffraction

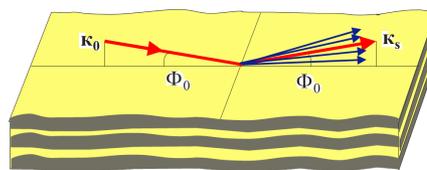
TER SL on the Web
 X-ray specular reflection from multilayers with rough interfaces at grazing incidence



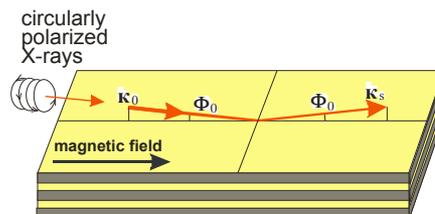
BRL on the Web
 X-ray multiple Bragg/Laue diffraction



TRDS SL on the Web
 X-ray diffuse scattering at grazing incidence from surface and interface roughness



MAG_SL on the Web
 X-ray resonant specular reflection from magnetic multilayers



Calculates resonant X-ray reflectivity from magnetic multilayers [Stepanov & Sinha, PRB. **61**, 16369 (2000)].

X-rays: Wavelength(A) / Energy(keV) = Line= ?

Polarization: angle to Sigma-plane for Option-3

Substrate: Database code: ? Chemical formula: rho= g/cm³

Susceptibility $\chi_0 = (\text{ })$ / format: $\chi_0 = (\text{Re}(\chi_0), \text{Im}(\chi_0))$; note: $\chi_0 = 2 * \delta /$

χ_0 correction: $w_0 =$ / this is used as: $\chi_0 = w_0 * \chi_0 /$

Roughness: sigma = Angstrom OR Transition layer tr = Angstrom

Magnetic atoms share (0.--1) / density (1/cm³):

Magnetic orientation X = Y = Z =

Magnetic amplitudes F10 = F11 = F1T =

Scan (incidence angle or qz): from to degr. Scan points=

Magnetic model: generic (may have numeric problems for hard x-rays) / hard x-rays (E>6keV)

watch progress (single click, please!)

Top layer profile (optional):

period=
t= sigma= tr= code= rho= x= code2= x2= code3= x3= code4= x0= w0=
mshare= mdensity= mvector= F10= F11= F1T=

end period

```

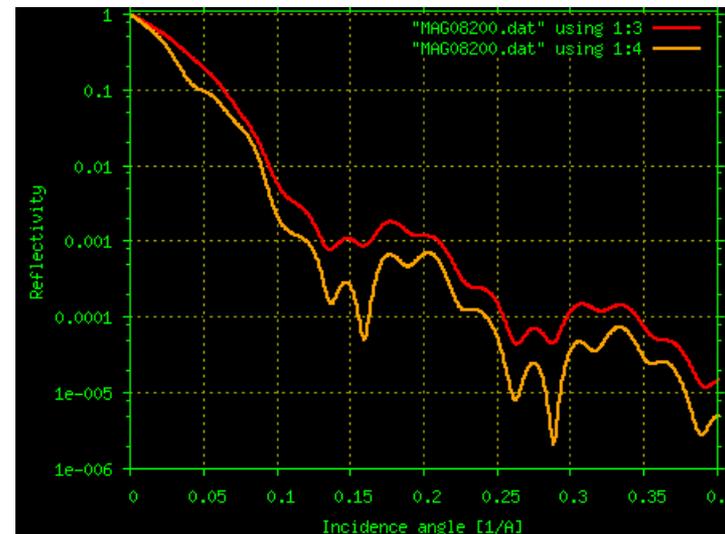
period=15
code=Gd t=50 F11=(-0.22,9.35) F1T=(0.37,9.65) mshare=1 mvector=(1 0 0)
code=Fe t=35
end period
    
```

(same "Submit" action as above; single click, please!)

Available codes:
(use Copy/Paste)

- Ac
- Ag
- Al
- Al2O3
- AlAs
- AlP
- AlSb
- AlYO3
- Am
- Ar
- As
- At
- Au
- B
- B4C

[More details](#)

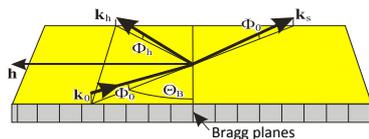


MAG_sl example: difference between reflectivity of circular-plus and circular-minus polarized X-rays at E=849eV from 47A capped Ni film.

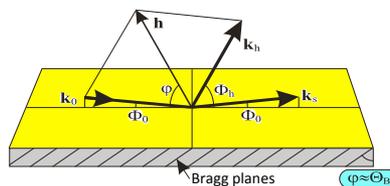
Web input form

X-Server scope: X0h (structure factors)

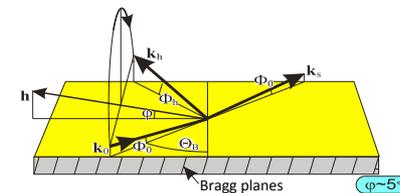
GID_SL on the Web
 Dynamical x-ray diffraction from strained crystals, multilayers and superlattices at usual and grazing incidence angles



Grazing incidence diffraction

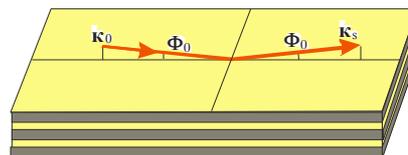


Extremely asymmetric diffraction

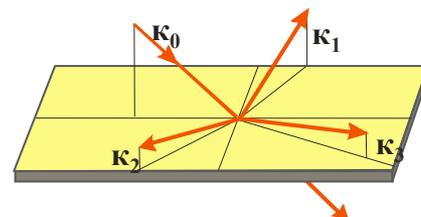


Any non-coplanar diffraction

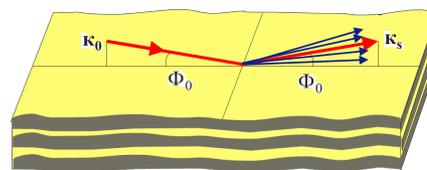
TER_SL on the Web
 X-ray specular reflection from multilayers with rough interfaces at grazing incidence



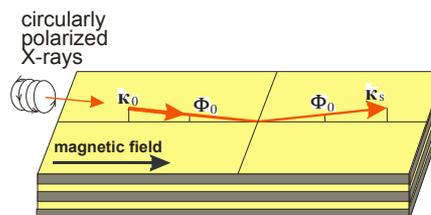
BRL on the Web
 X-ray multiple Bragg/Laue diffraction



TRDS_SL on the Web
 X-ray diffuse scattering at grazing incidence from surface and interface roughness



MAG_SL on the Web
 X-ray resonant specular reflection from magnetic multilayers



X0h on the Web !!

- Provides X-ray scattering factors for all X-Server programs.
- Interpolates data of three different tables with option to compare.

X-rays:

Wavelength (Å):
 Energy (keV):
 Characteristic line: Cu-Kα1 ?

Target:

Crystal: Silicon ?
 Other material: ?
 Chemical formula: and density (g/cm³):

Reflection:

Miller indices:

Database Options for dispersion corrections df1, df2:

Auto (Henke at low energy, X0h at mid, Brennan-Cowan at high).
 Use X0h data (5-25 keV or 0.5-2.5 Å) -- recommended for Bragg diffraction.
 Use Henke data (0.01-30 keV or 0.4-1200 Å) -- recommended for soft x-rays.
 Use Brennan-Cowan data (0.03-700 keV or 0.02-400 Å)
 Compare results for all of the above sources.

Output Options:

Print atomic coordinates
 Text-form output

X-rays:

Wavelength (Å):
 Energy (keV):
 Characteristic line: Cu-Kα1 ?

Crystal:

Select code: Silicon ?

Bragg planes range:

From: To:

Bragg angle range:

From: To:

Intensity control:

Minimum | χ_h/χ_0 | (%):

Database option for dispersion corrections df1, df2:

Use X0h data (5-25 keV or 0.5-2.5 Å) -- recommended for Bragg diffraction.
 Use Henke data (0.01-30 keV or 0.4-1200 Å) -- recommended for soft x-rays.
 Use Brennan-Cowan data (0.03-700 keV or 0.02-400 Å)

Find only those Bragg planes which make certain angles to the surface:

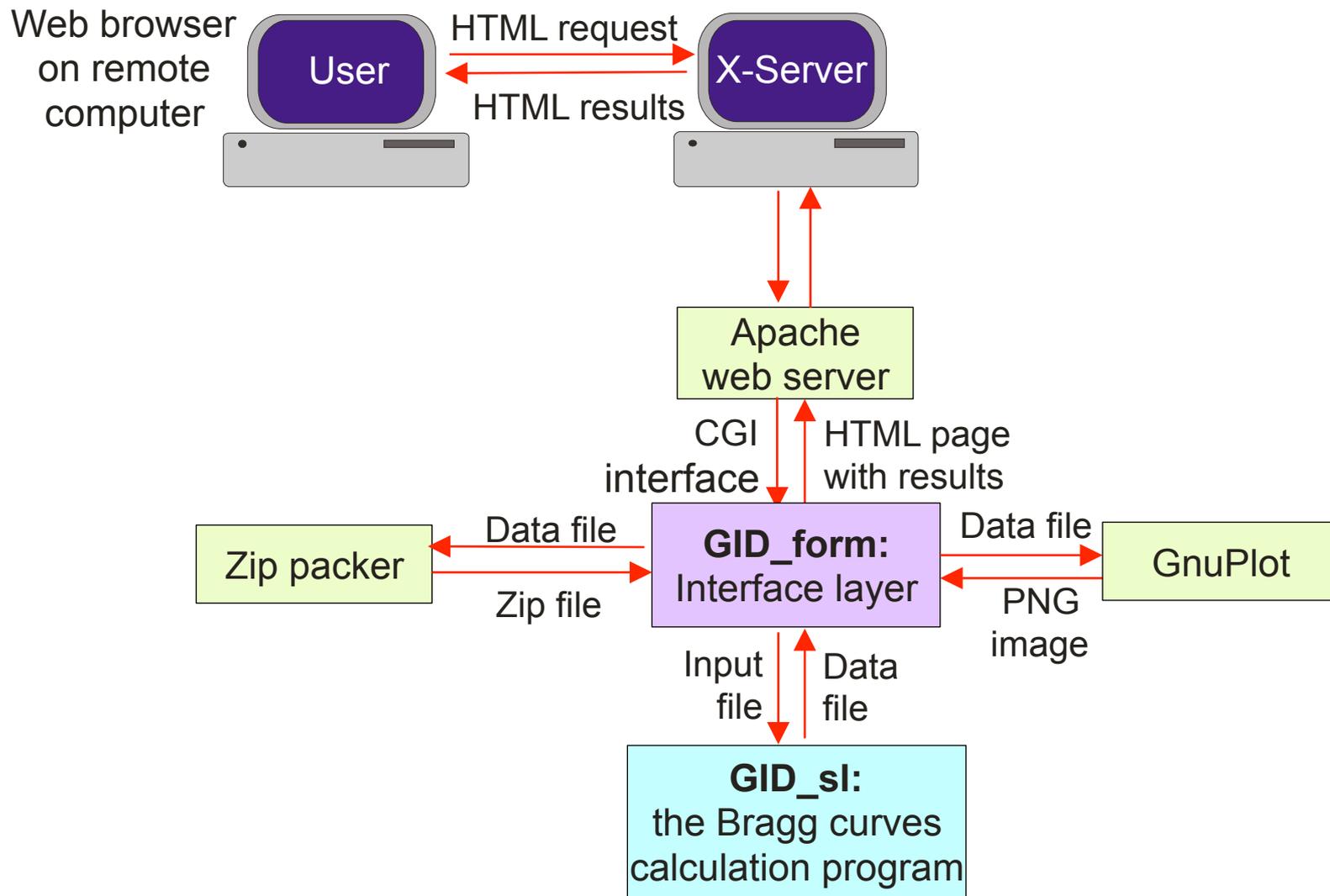
Surface plane indices:

Planes make angles from Theta1 to Theta2
 Planes make angles from Theta1 to (Bragg_Angle - Theta2)
 Planes make angles from (Bragg_Angle - Theta1) to (Bragg_Angle - Theta2)

Theta1: Theta2:

Web input forms

How X-Server works



Server access is not limited to web browsers

X-rays:

Wavelength (Å):

Energy (keV):

Characteristic line: ?

Target:

Crystal: ?

Other material: ?

Chemical formula: and density (g/cm³):

Reflection:

Miller indices:

Database Options for dispersion corrections df_1 , df_2 :

Auto (Henke at low energy, X0h at mid, Brennan-Cowan at high).

Use X0h data (5-25 keV or 0.5-2.5 Å) -- recommended for Bragg diffraction.

Use Henke data (0.01-30 keV or 0.4-1200 Å) -- recommended for soft x-rays.

Use Brennan-Cowan data (0.03-700 keV or 0.02-400 Å)

Compare results for all of the above sources.

Output Options:

Print atomic coordinates

Text-form output

This is a web browser form of X0h.
What happens when one clicks the
“Get X0h!” button?

Server access is not limited to web browsers

The image shows a screenshot of a web form for X-ray diffraction calculations. The form is divided into several sections, each with a red header. Blue boxes with arrows point to specific input fields, highlighting the parameters that are passed to the X-Server as named parameters.

- X-rays:**
 - Wavelength (A): 10 (labeled **wave**)
 - Energy (keV): (labeled **code**)
 - Characteristic line: Cu-Ka1 (labeled **code**)
- Target:**
 - Crystal: Silicon (labeled **coway**)
 - Other material: (labeled **code**)
 - Chemical formula: and density (g/cm³):
- Reflection:**
 - Miller indices: 1 1 1 (labeled **i1**, **i2**, **i3**)
 - (labeled **df1df2**)
- Database Options for dispersion corrections df1, df2:**
 - Auto (Henke at low energy, X0h at mid, Brennan-Cowan at high).
 - Use X0h data (5-25 keV or 0.5-2.5 A) -- recommended for Bragg diffraction.
 - Use Henke data (0.01-30 keV or 0.4-1200 A) -- recommended for soft x-rays.
 - Use Brennan-Cowan data (0.03-700 keV or 0.02-400 A)
 - Compare results for all of the above sources.
- Output Options:**
 - Print atomic coordinates (labeled **detail**)
 - Text-form output (labeled **modeout**)

Buttons: Get X0h! Reset

Behind each input on the web browser form there is a named parameter which the browser sends to X-Server upon clicking the “Get X0h!” button.

Server access is not limited to web browsers

The image shows a web form for X-ray diffraction calculations. Blue boxes with arrows point to various fields, indicating their corresponding command-line parameters:

- xway** points to the form's title.
- wave** points to the Wavelength (A) input field (value: 10).
- code** points to the Characteristic line dropdown menu (value: Cu-Ka1).
- coway** points to the Crystal dropdown menu (value: Silicon).
- i1**, **i2**, and **i3** point to the Miller indices input fields (values: 1, 1, 1).
- df1df2** points to the Database Options section.
- detail** points to the Print atomic coordinates checkbox.
- modeout** points to the Text-form output checkbox.

Buttons at the bottom include "Get X0h!" and "Reset".

Then, one can simply use curl or other command-line program to submit the request:

```
curl http://x-server.gmca.aps.anl.gov/cgi/x0h_form.exe?xway=2\&wave=10\&coway=0  
\&code=Silicon\&i1=1\&i2=1\&i3=1 > results.file
```

Server access is not limited to web browsers

xway

X-rays:

Wavelength (A): 10 **wave**

Energy (keV):

Characteristic line: Cu-Ka1 ? **code**

Target:

Crystal: Silicon **coway** ?

Other material: ?

Chemical formula: and density (g/cm³):

Reflection:

Miller indices: **i1** **i2** **i3**

1 1 1 **df1df2**

Database Options for dispersion corrections df1, df2:

Auto (Henke at low energy, X0h at mid, Brennan-Cowan at high energy)

Use X0h data (5-25 keV or 0.5-2.5 A) -- recommended for Bragg

Use Henke data (0.01-30 keV or 0.4-1200 A) -- recommended for

Use Brennan-Cowan data (0.03-700 keV or 0.02-400 A)

Compare results for all of the above sources.

Output Options:

Print atomic coordinates **detail**

Text-form output **modeout**

Get X0h! Reset

One can also do the same type of call from almost any scripting or programming language:

```
#!/usr/bin/perl
use LWP::Simple;
$url = 'http://x-server.gmca.aps.anl.gov/cgi/x0h_form.exe';
$FORM{'xway'} = 2;
$FORM{'wave'} = 10;
$FORM{'coway'} = 0;
$FORM{'code'} = 'Silicon';
($FORM{'i1'}, $FORM{'i2'}, $FORM{'i3'}) = (1, 1, 1);
$FORM{'df1df2'} = -1;
$FORM{'detail'} = 0;
$FORM{'modeout'} = 1;
$request = '';
foreach $key (keys %FORM) {$request .= '&'.$key.'='.$FORM{$key};}
$request =~ s/^\&/\?/;
$buffer = get($url.$request);
print $buffer;
```

Downloadable examples of X-Server access scripts

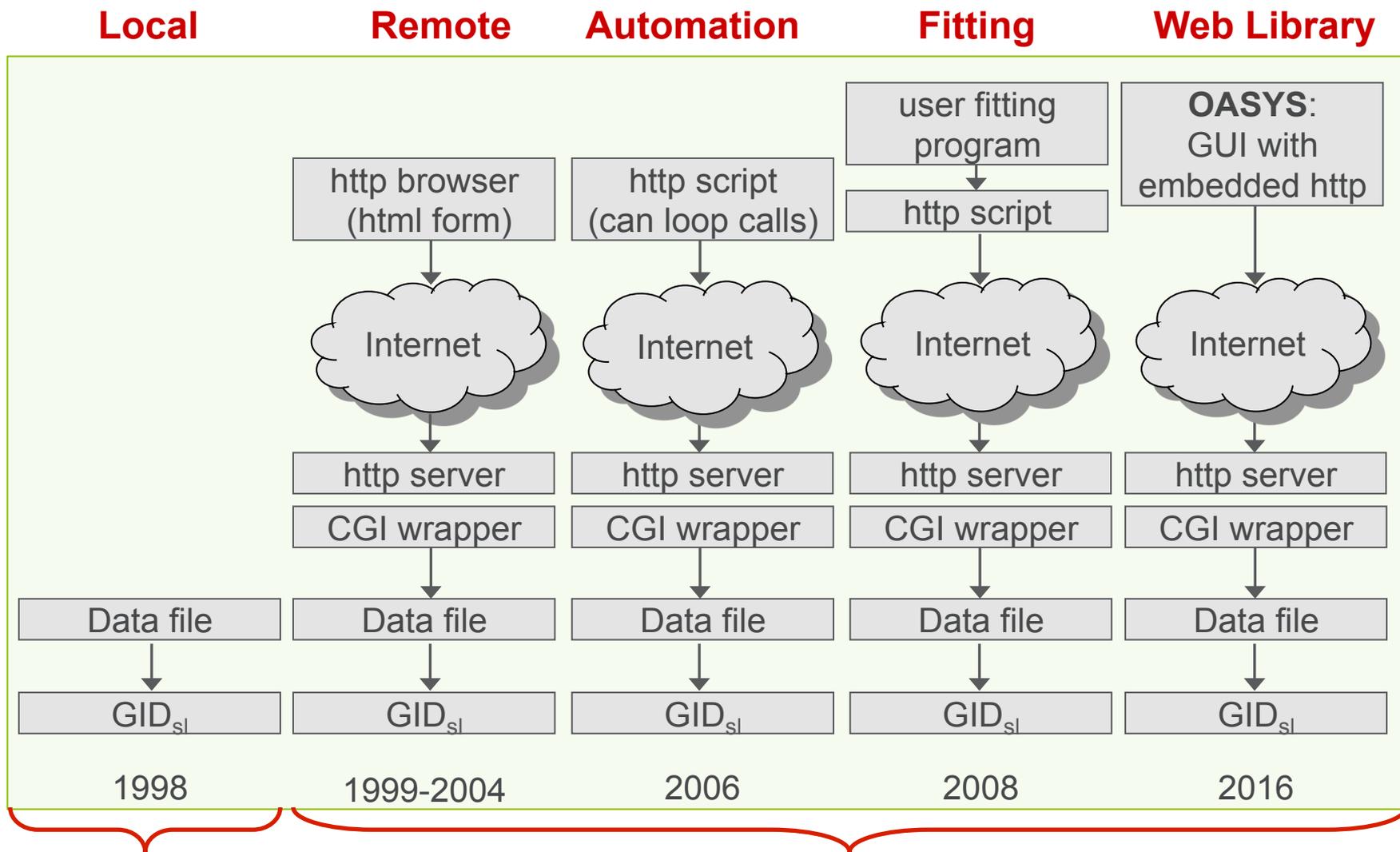
<http://x-server.gmca.aps.anl.gov/automation.html>

getX0h.pl	Script interfacing <i>X0h</i>	(equivalent to <i>X0h</i> form)
getGID.pl	Script interfacing <i>GID_sl</i>	(equivalent to <i>GID_sl</i> form)
getTER.pl	Script interfacing <i>TER_sl</i>	(equivalent to <i>TER_sl</i> form)
getTER_sw.pl	A script interfacing <i>TER_sl</i> and additionally requesting standing waves	(equivalent to <i>TER_sl</i> form)

The scripts can be called from user's software written in any language using the **system** function. If one needs to vary a parameter, it can be passed to the script as a command line argument.

These scripts present a practical example of client software accessing the server programs. They are simple, but they **should be simple** to become useful since they address a wide auditory of physicists presumably unexperienced in web interfaces.

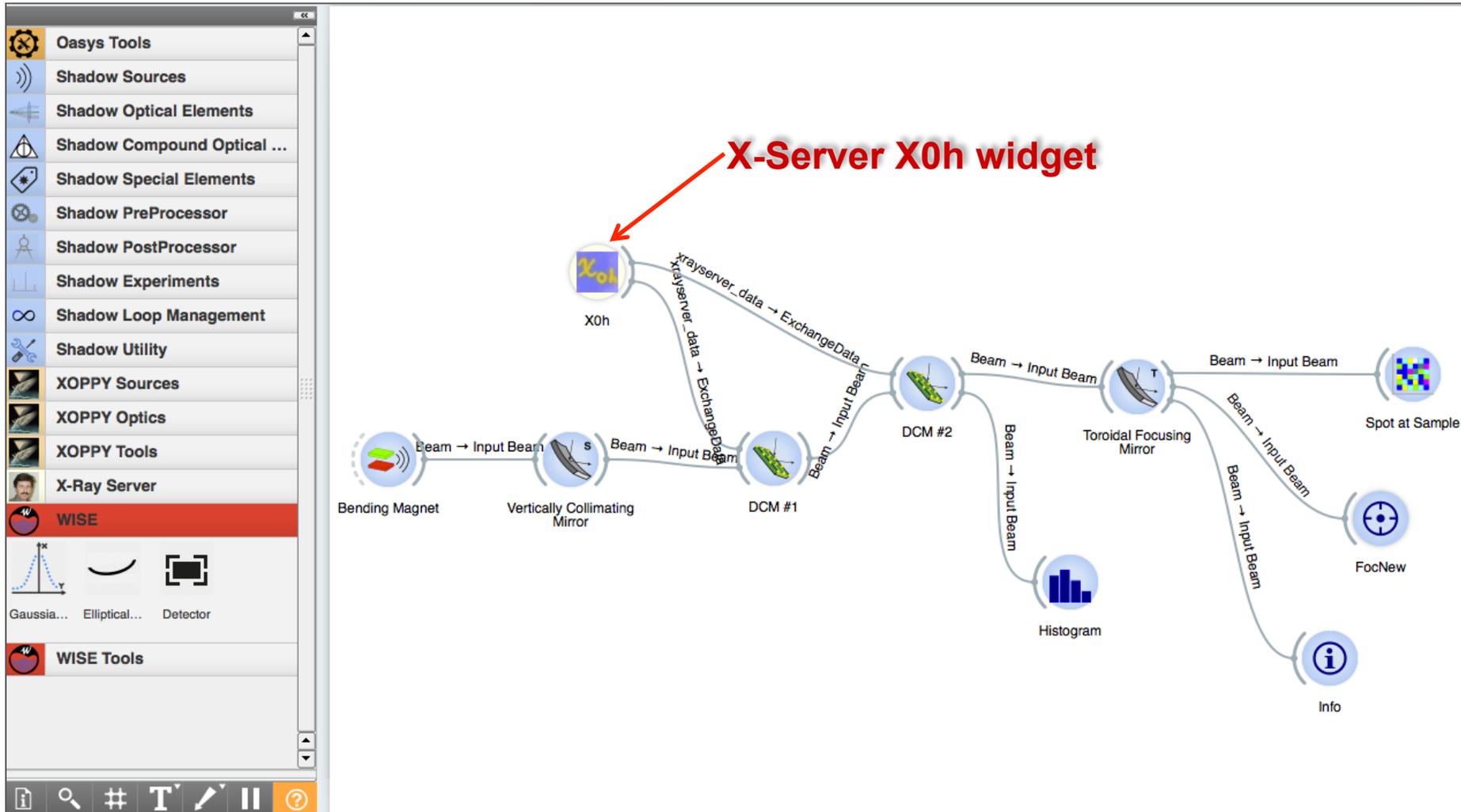
X-Server access evolution



Developed for
a paper

X-Ray Server

OASYS: new level of interaction with X-Server



X-Server access is embedded into Oasys and user does not need to do any programming; just add the X-Server widgets.

OASYS: new level of interaction with X-Server

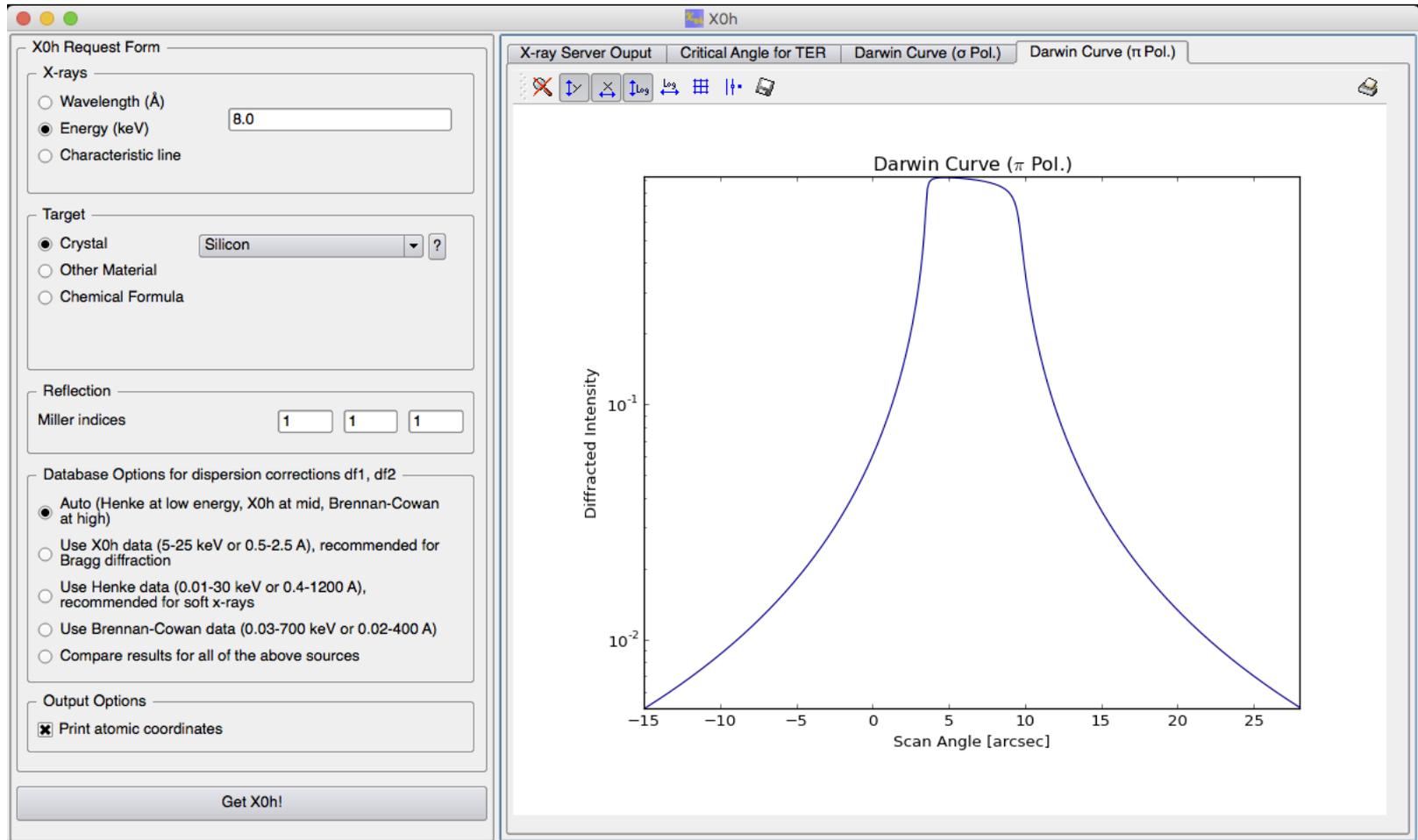
The screenshot displays the X0h software interface. On the left is the 'X0h Request Form' with several sections: 'X-rays' (Wavelength in Å, Energy in keV, Characteristic line), 'Target' (Crystal, Other Material, Chemical Formula), 'Reflection' (Miller indices), 'Database Options for dispersion corrections df1, df2' (Auto, Use X0h data, Use Henke data, Use Brennan-Cowan data, Compare results), and 'Output Options' (Print atomic coordinates). A 'Get X0h!' button is at the bottom.

On the right is the 'X-ray Server Output' window, showing 'Job ID: x1263437' and 'X0h Results for 140.105.207.245 [207-245.elettra.trieste.it:]'. It contains a table of structure factors and other parameters:

Structure :	Silicon
Symmetry :	Cubic
Density (gm/cm ³) :	2.3293
Unit cell constants (A) :	5.4309 , 5.4309 , 5.4309
Unit cell angles (degr.) :	90.000 , 90.000 , 90.000
Poisson Ratio :	0.2800
Composition: Element -- N_sites (sites occupation) ... Element x,y,z :	Si -- 8 (1.000) 0.00000, 0.00000, 0.00000 0.50000, 0.50000, 0.00000 0.50000, 0.00000, 0.50000 0.00000, 0.50000, 0.50000 0.25000, 0.25000, 0.75000 0.25000, 0.75000, 0.25000 0.75000, 0.25000, 0.25000 0.75000, 0.75000, 0.75000
X-ray line :	none
Wavelength (A) :	1.5498
Energy (keV) :	8.
Closest absorption edge (keV) :	1.84 (for element Si)
Database for df ₁ , df ₂ :	*** Automatic DB choice ***
x _{r0} , x _{i0} (n = 1 + x _{r0} /2 + i*x _{i0} /2) :	-0.15310E-04 , 0.35784E-06
delta , eta (n = 1 - delta - i*eta) :	0.76552E-05 , -0.17892E-06
Absorption factor (1/cm) and length (um) :	145.07 , 68.931
Extinction length at TER (A) :	63.030
Critical angle for TER (degr., mrad) :	0.22422 , 3.9134
Reflection :	(1 1 1)
Bragg angle (degr.) :	14.308
Interplanar spacing (A) :	3.1355
sin(QB) , cos(QB) :	0.24714 , 0.96898
tan(QB) , cotan(QB) :	0.25505 , 3.9208

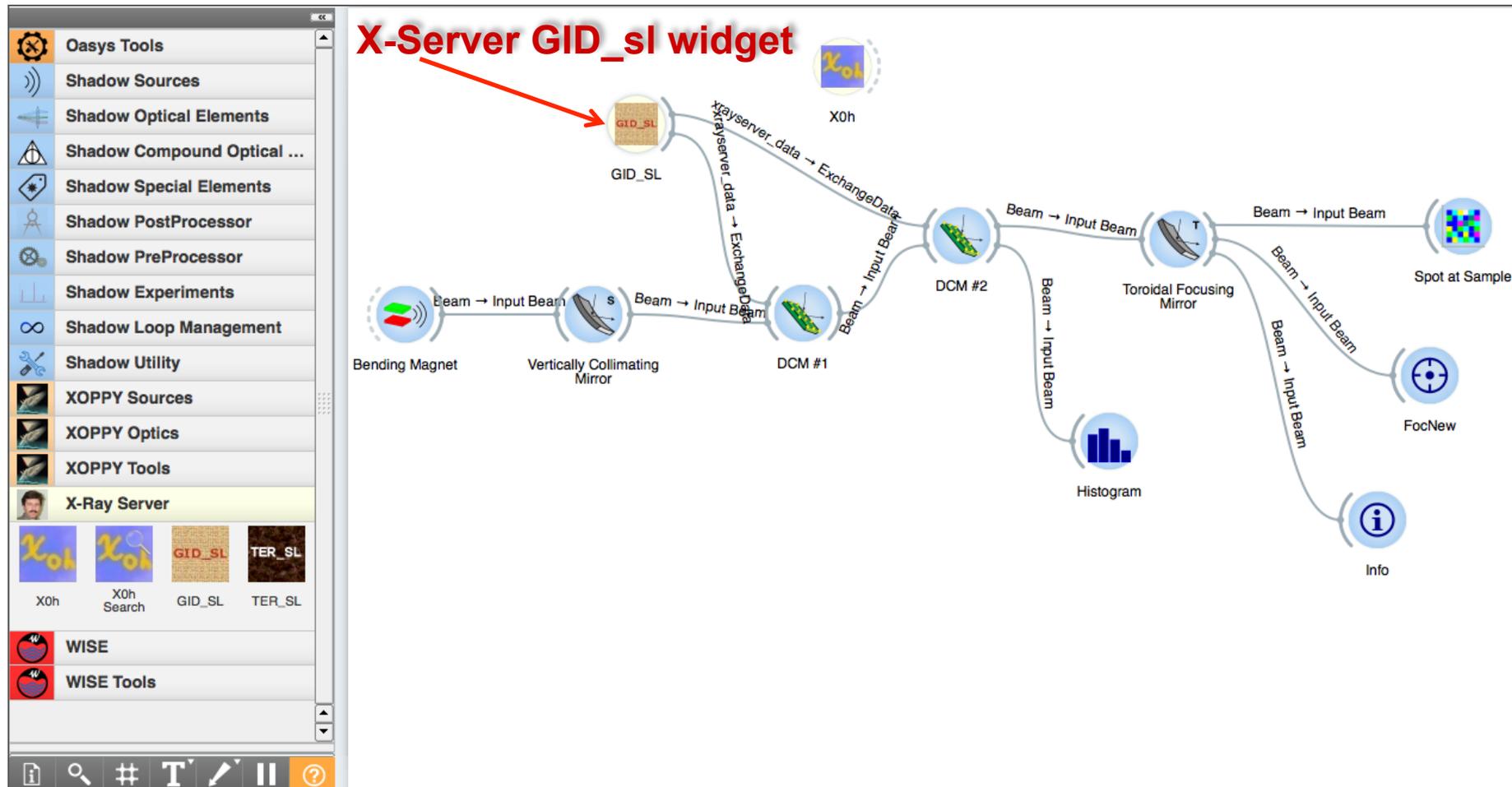
Once the widget is added to the Oasys diagram, it allows to retrieve the structure factors ...

OASYS: new level of interaction with X-Server



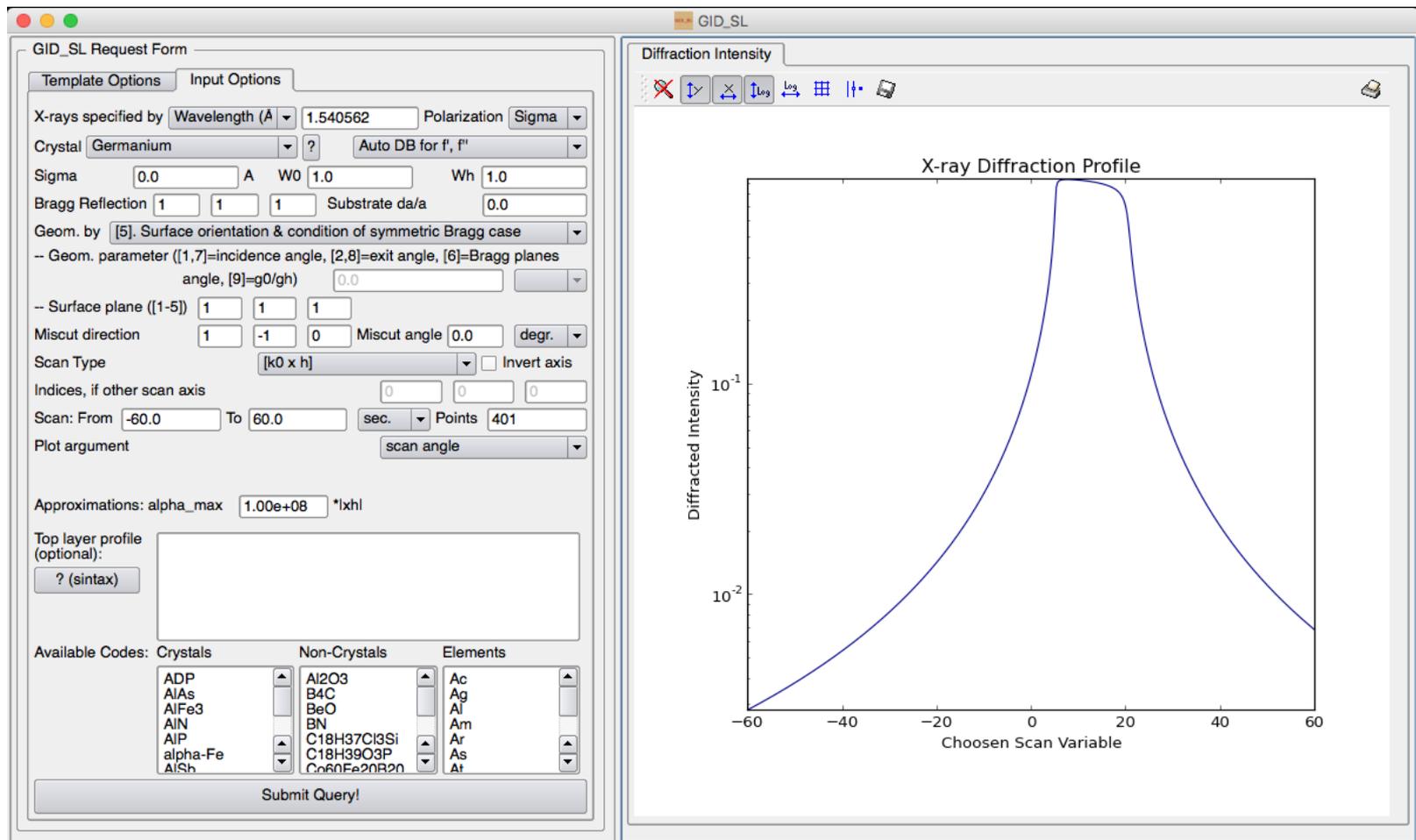
... and associated Darwin curves for σ - and π - X-ray polarizations

OASYS: new level of interaction with X-Server



Same way one can include the GID_sl and TER_sl widgets

OASYS: new level of interaction with X-Server



... and fetch their data. Note that the surface layer profile can be entered too

Why no server-side data fitting & instrument convolution?

X-rays: Wavelength(A) / Energy(keV) = Line=Cu-Ka1 Polarization=

Crystal: Sigma= A W0= Wh=

Bragg Reflection: Substrate da/a=

Geometry specified by: , Value:

Scan: from to Scan points: Invert axis: Plot argument:

Approximations: alpha_max= *|xh|

watch progress (single click, please!)

Top layer profile (optional):

t=	sigma=	da/a=	code=	x=	code2=	x2=	code3=	x3=	code4=	x0=	xh=	xhdf=	w0=	wh=
800		0.00048												0.971610767
800		0.00048128												0.97153615
800		0.00048128												0.97153615
800		0.00048512												0.971312334
800		0.0004864												0.97123774
800		0.00049024												0.971013993
800		0.00049408												0.970790297
800		0.0004992												0.970492116
800		0.0005056												0.970119519
800		0.00051328												0.969672591
800		0.00052224												0.969151435
800		0.00053376												0.968481789
800		0.00054656												0.96773828
800		0.0005632												0.966772572
800		0.00058112												0.965733657
800		0.0006016												0.964547692
800		0.00062336												0.963289201
800		0.00065536												0.96144146
800		0.00068608												0.959670963
800		0.0007168												0.957903727
800		0.0007616												0.95532339

(same "Submit" action as above; single click, please!)

Available codes:

Crystals:

- AlAs
- AlFe3
- AlN
- AlP
- alpha-Fe
- AlSb
- AlY03

Non-crystals:

- Al2O3
- B4C
- BeO
- BN
- Cr2O3
- CsI
- Fluorite

Elements:

- Ac
- Ag
- Al
- Am
- Ar
- As
- At
- Au

Providing Server-side fitting for all cases is non-practical:
Too many parameters!

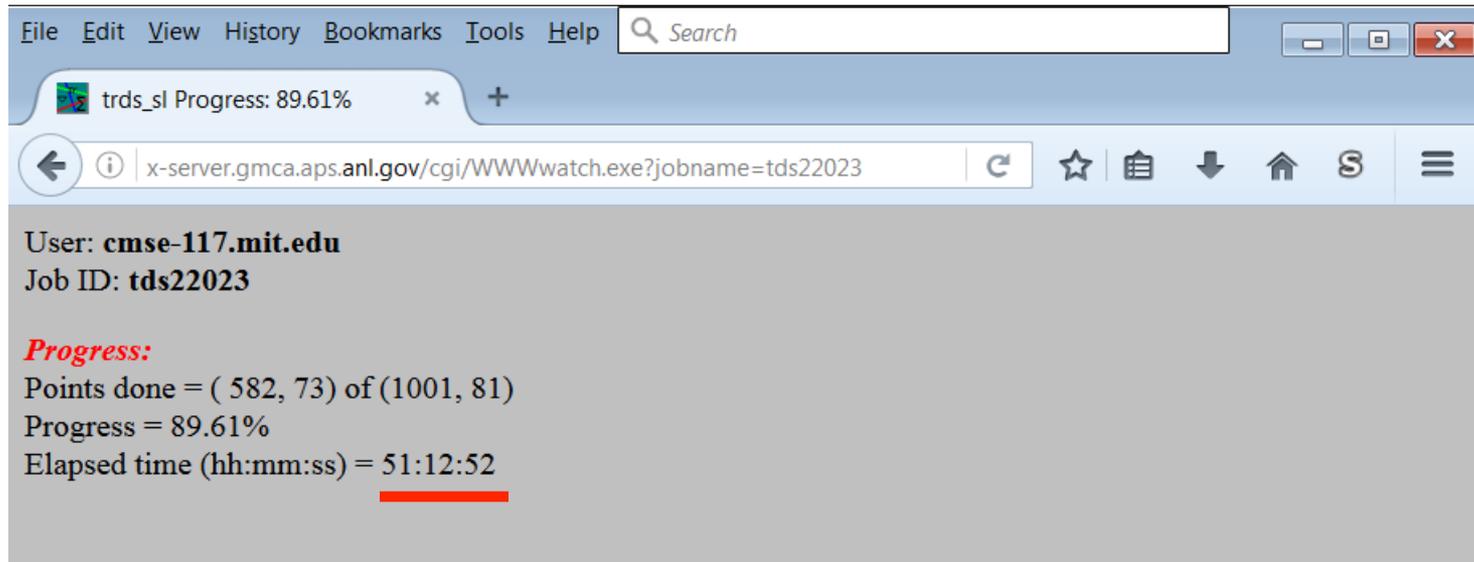
The form at the left is a typical material science application submitted from univ-poitiers.fr. The profile contains 72 lines, i.e. more than 200 parameters.

Also, account for the geometry or resolution of experiment would make the programs **case-specific** vs general.

Suggested solution: the Server programs can be used as a library providing Bragg or reflection curves to user's software doing fitting or instrument convolution.

Server overhead & handling of lengthy calculations

- ❑ The Server overhead was studied by Stepanov & Forrest, [J. Appl. Cryst. 41, 958 (2008)] where X-ray Bragg reflection profiles from superlattices were fitted with the help of X-Server. The observed overhead was 2.9s per request, which in that case corresponded to less than 10%, but the percentage could be less or more depending on the duration of calculation.
- ❑ Most of the Server programs return results within several minutes or less. The only exception could be TRDS_sl where the length of calculations is proportional to the 4th power of the number of interfaces. When user submits a job, he can check the “**watch progress**” option. Then, the job ID is returned immediately and user can disconnect and come back later to check the progress and download the results:



Current restrictions & further plans

- ❑ GID_sl currently accounts for specular reflection of X-rays in all cases. It needs to do it for grazing X-rays only, which will result in up to 4x faster and digitally more stable calculations.
- ❑ GID_sl can be supplied with the printout of X-ray standing waves.
- ❑ TER_sl needs to be supplied with energy scans.
- ❑ BRL needs an update to the recursion matrix algorithm similar to that used in the other programs for more stable operation on thick crystals.
- ❑ Automatic submission of crystal structures is considered, but still questionable. Currently new structures can be added per users submissions (a template is provided at http://x-server.gmca.aps.anl.gov/structure_submission_example.txt). Then, I verify them with the space group generator and typically add to the X0h DB within a day. Unfortunately, the rate of mistakes in users submissions is very high and supplying the user community with mistaken structures does not look as a good idea. Most of calculations can be done by directly specifying the structure factors and thus bypassing the X0h DB, which is simply a convenience.

Conclusions

- ❑ We have a well refined resource for the calculations of X-ray dynamical diffraction, specular reflection and diffuse scattering with almost 20 years of online history.
- ❑ The main applications are X-ray optics and X-ray material science.
- ❑ To get most of this resource, e.g. implement data fitting, one needs to use tools beyond web browser.
- ❑ Examples are provided to write such tools on your own, but for some tasks one can use already developed tools like Oasys (to be released soon).
- ❑ Users are welcome to share the tools they developed: these tools can be hosted on the server for the benefit of the whole community – same way as any user-submitted structures are available to everyone using the server.

Acknowledgements

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I also thank many X-Ray Server users for providing their valuable feedback and suggestions and for submitting new structures.